Record Nr.	UNINA9910153303403321
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Titolo	Energy-Level Control at Hybrid Inorganic/Organic Semiconductor Interfaces / / by Raphael Schlesinger
Pubbl/distr/stampa	Cham : , : Springer International Publishing : , : Imprint : Springer, , 2017
ISBN	3-319-46624-0
Edizione	[1st ed. 2017.]
Descrizione fisica	1 online resource (XVIII, 211 p. 88 illus., 52 illus. in color.)
Collana	Springer Theses, Recognizing Outstanding Ph.D. Research, , 2190- 5053
Disciplina	537.622
Soggetti	Surfaces (Physics)
	Interfaces (Physical sciences)
	Thin films
	Optical materials
	Microscopy
	Semiconductors
	Surface and Interface Science. Thin Films
	Optical and Electronic Materials
	Spectroscopy and Microscopy
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	"Doctoral Thesis accepted by the Humboldt University of Berlin, Germany."
Nota di bibliografia	Includes bibliographical references at the end of each chapters.
Nota di contenuto	Introduction Fundamentals Theory of Experimental Methods Methodology and Experimental Setups Results and Discussion Conclusion
Sommario/riassunto	This work investigates the energy-level alignment of hybrid inorganic/organic systems (HIOS) comprising ZnO as the major inorganic semiconductor. In addition to offering essential insights, the thesis demonstrates HIOS energy-level alignment tuning within an unprecedented energy range. (Sub)monolayers of organic molecular donors and acceptors are introduced as an interlayer to modify HIOS interface-energy levels. By studying numerous HIOS with varying

properties, the author derives generally valid systematic insights into the fundamental processes at work. In addition to molecular pinning levels, he identifies adsorption-induced band bending and gap-state density of states as playing a crucial role in the interlayer-modified energy-level alignment, thus laying the foundation for rationally controlling HIOS interface electronic properties. The thesis also presents quantitative descriptions of many aspects of the processes, opening the door for innovative HIOS interfaces and for future applications of ZnO in electronic devices.